

Date Created : 2009/08/11
Date Issued On : 2009/09/10
PCN# : Q3093302

INFORMATION ONLY NOTIFICATION

This minor change has passed all the requirements based on the evaluation plan. Reports are available to support this change. If you require data or samples regarding this change, please contact Fairchild Semiconductor within 30 days of receipt of this notification.

This is to inform you that a minor change is being made to the following product(s). This notification is for your information only.

If you have any questions concerning this change, please contact:

Technical Contact:
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E-mail: Joel.Baring@notes.fairchildsemi.com
Phone: 5165

PCN Originator:
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Phone: (63 32) 3400534 loc 5452

Implementation of change:
Expected 1st Device Shipment Date: 2009/09/20

Earliest Year/Work Week of Changed Product: 0939

Change Type Description: Process Flow

Description of Change (From): Singulated Testing

Description of Change (To): Wafer Level Testing

Reason for Change : To provide immediate electrical performance feedback to our wafer fabrication facility.

Product Id Description : This change will affect Discrete product(s) assembled in WLCSP 1x1.5 package in Cebu Philippines facility. The product(s) affected by this change is listed in the "Affected FSIDs" section.

Affected FSIDs :

FDZ191P		
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